



Probe model	FAI3.3-150		
Version description	FAI3.3-150 shaft length 150 mm		
Part no.	604-187		
	FAI3.3-260 shaft length 260 mm		
	604-336		
Probe design	Single tip inside probe with spring-loaded measuring system	<i>Mechanical design principle of the measurement probe.</i>	
Measuring mode	Single mode	<i>Specifies, whether this probe is suitable for only one (single mode), for several (DUAL mode) or for a combination of two methods (DUPLICATE mode).</i>	
Measuring method	Eddy current method	<i>Method used for the specified measuring application.</i>	
Measuring application	Iso/NF	<i>Measurable coating/substrate material system.</i>	
Measuring range	0 - 800 µm	<i>Limits of the measurable coating thickness.</i>	
Accuracy	1 - 200 µm: 1 µm 200 - 800 µm: < 0.5 %	<i>The trueness is determined using calibration standards of known thicknesses. It is the difference between the nominal value of the calibration standard and the measured value. The trueness can be stated as an absolute value or as a percentage of the reading.</i>	
Precision	1 - 100 µm: 0.3 µm 100 - 800 µm: 0.3 %	<i>Repeatable standard deviation s of n = 10 single readings.</i>	
Ø (concave) for 10 % error	55 mm 9 mm	2.2" 360 mils	<i>Diameter of a specimen with a concave curvature, under which the error is > 10 %. Min. Ø: Smallest diameter permissible for measurements.</i>
Ø (convex) for 10 % error	50 mm 2 mm	2" 80 mils	<i>Diameter of a specimen with a convex curvature, under which the error is > 10 %. Min. Ø: Smallest diameter permissible for a measurement.</i>
Meas. area Ø for 10 % error	4 mm 2 mm	160 mils 80 mils	<i>Diameter of a flat measurement area, under which the error is > 10 %. Min. Ø: Smallest diameter permissible for a measurement.</i>
Edge distance for 10 % error	-	-	<i>Distance of the probe tip to the edge of the specimen underneath which the error is > 10 %. For 2-tip probes: Parallel distance tip connection line to the edge.</i>
Substrate th. for 10 % error	0.09 mm	4 mils	<i>This the thickness d of the substrate material, under which the reading will deviate by more than 10 % from an "infinitely" thick substrate material.</i>
Probe tip radius	1.2 mm	48 mils	<i>Radius of the probe measuring tip. The measuring tip establishes the contact with the surface of the specimen.</i>
Probe tip material	Sapphire jewel tip	<i>Material of the measuring tip.</i>	
Probe tip replaceable	Yes	<i>Specifies, whether a worn measuring tip can be replaced or not.</i>	
Height	6,5 mm	<i>Ref. graphic in the section „Note regarding the probe dimensions“</i>	
Diameter / width	5,5 mm	<i>Ref. graphic in the section „Note regarding the probe dimensions“</i>	
Length	Depending on version	<i>Ref. graphic in the section „Note regarding the probe dimensions“</i>	
Works with the instruments	FMP10/20/30/40/100, MMS® PC & F-Modul PERMAS-COPE®	<i>Designation of the HELMUT FISCHER instruments to which the respective probe can be connected.</i>	
Applications	Measures electrically non-conducting coatings on non-ferromagnetic metal substrate materials (Iso/NF). Suited for measurements in pipes, bore holes, grooves, etc. External start should be used to avoid contact errors. Smallest permissible inside diameter: 9 mm. Maximum insertion depth: 150 mm.	<i>Abbreviations:</i> NF: Non-ferrous metals (non-ferromagnetic properties). Fe: Iron or steel (with ferromagnetic properties). Iso: Material with isolating properties, i.e., electrically non-conducting e.g., paint. *) The limits are referenced to a coating thickness that generates a measuring signal at about the center of the usable signal range. With increasing coating thicknesses, the 10 % error will be reached only at smaller radii or substrate material thicknesses, respectively.	